

Notice of References Cited			Application/Control No. 09/982,964	Applicant(s)/Patent Under Reexamination NAKAMURA ET AL.	
			Examiner Jeffrey T Barton	Art Unit 1753	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,207,031	03-2001	Adourian et al.	204/451
	B	US-5,483,075	01-1996	Smith et al.	250/458.1
	C	US-5,627,643	05-1997	Birnbaum et al.	356/344
	D	US-5,137,609	08-1992	Manian et al.	204/452
	E	US-5,038,021	08-1991	Uchigaki et al.	235/375
	F	US-5,759,369	06-1998	Menchen et al.	204/456
	G	US-6,132,579	10-2000	Edwards et al.	204/451
	H	US-6,126,804	10-2000	Andresen, Brian D.	204/601
	I	US-5,958,202	09-1999	Regnier et al.	204/451
	J	US-5,954,931	09-1999	Maracas et al.	204/451
	K	US-6,042,708	03-2000	Nakanishi et al.	204/452
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	EP 934771 A1	08-1999	European Patent	EDWARDS et al.	B01D 57/02
*	O	JP 10132783 A	05-1998	Japan	NAKANISHI et al.	G01N 27/447
*	P	JP 2000227414 A	08-2000	Japan	TANAKA, HIROSHI	G01N 27/447
*	Q	JP 2000283960 A	10-2000	Japan	TANAKA, HIROSHI	G01N 27/447
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Yining Shi et al, Anal. Chem. 1999, 71, 5354-5361.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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